

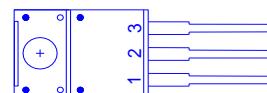
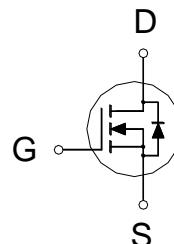
**NIKO-SEM**
**N-Channel Enhancement Mode  
Field Effect Transistor**
**P0260ETF**

TO-220F

Halogen-Free &amp; Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
600V	$4.3\Omega$	2A



1. GATE
2. DRAIN
3. SOURCE

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ C$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	$V_{DS}$	600	V
Gate-Source Voltage	$V_{GS}$	$\pm 30$	V
Continuous Drain Current <sup>2</sup>	$I_D$	2	A
		1.3	
Pulsed Drain Current <sup>1, 2</sup>	$I_{DM}$	8	A
Avalanche Current <sup>3</sup>	$I_{AS}$	2	
Avalanche Energy <sup>3</sup>	$E_{AS}$	20	mJ
Power Dissipation	$P_D$	29	W
		11	
Operating Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		4.3	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	

<sup>1</sup>Pulse width limited by maximum junction temperature.<sup>2</sup>Limited only by maximum temperature allowed<sup>3</sup> $V_{DD} = 50V$ ,  $L = 10mH$ , starting  $T_J = 25^\circ C$ **ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ C$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	600			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2	3	4	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 30V$			$\pm 100$	nA
Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 600V, V_{GS} = 0V, T_C = 25^\circ C$			1	$\mu A$
		$V_{DS} = 480V, V_{GS} = 0V, T_C = 100^\circ C$			10	

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Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 1A$		3.4	4.3	$\Omega$
Forward Transconductance <sup>1</sup>	$g_f$	$V_{DS} = 15V, I_D = 2A$		4		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		322		pF
Output Capacitance	$C_{oss}$			41		
Reverse Transfer Capacitance	$C_{rss}$			9		
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{DD} = 480V, I_D = 2A, V_{GS} = 10V$		10.7		nC
Gate-Source Charge <sup>2</sup>	$Q_{gs}$			1.4		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$			4.8		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	$V_{GS} = 10V, V_{DD} = 300V,$ $I_D = 2A, R_G = 25\Omega$		30		nS
Rise Time <sup>2</sup>	$t_r$			61		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$			59		
Fall Time <sup>2</sup>	$t_f$			67		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ C</math>)</b>						
Continuous Current <sup>3</sup>	$I_S$				2	A
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 2A, V_{GS} = 0V$			1.5	V
Reverse Recovery Time	$t_{rr}$	$I_F = 2A, dI_F/dt = 100A/\mu S$		295		nS
Reverse Recovery Charge	$Q_{rr}$			1.2		uC

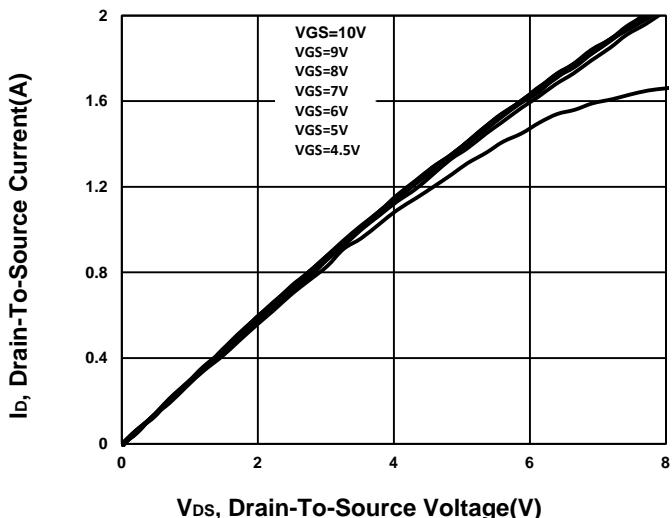
<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.<sup>3</sup>Pulse width limited by maximum junction temperature.

**NIKO-SEM**

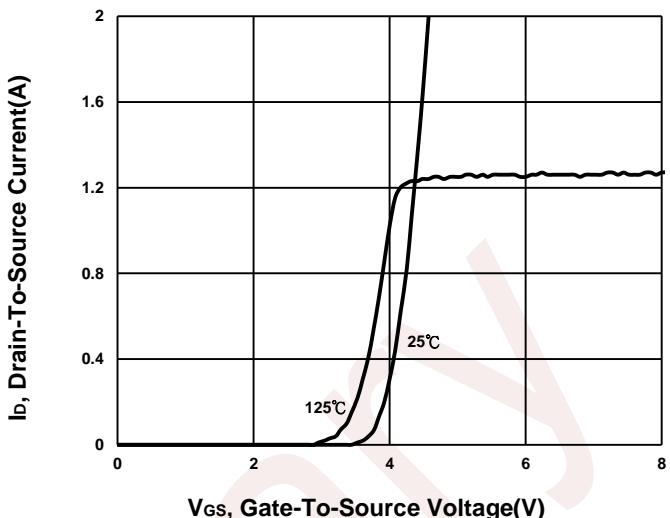
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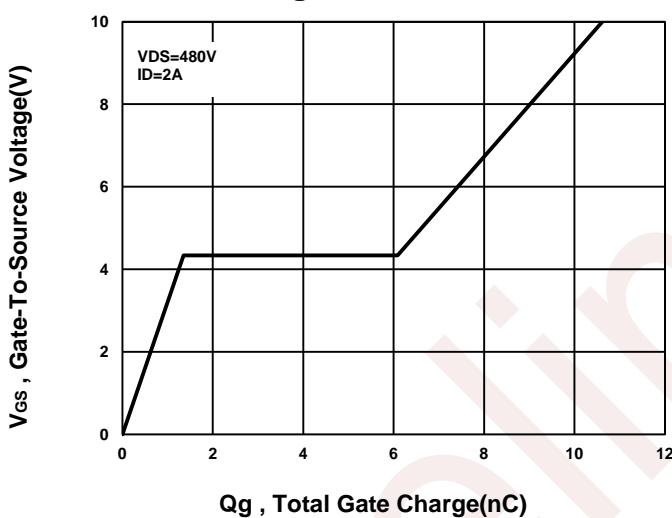
**Output Characteristics**



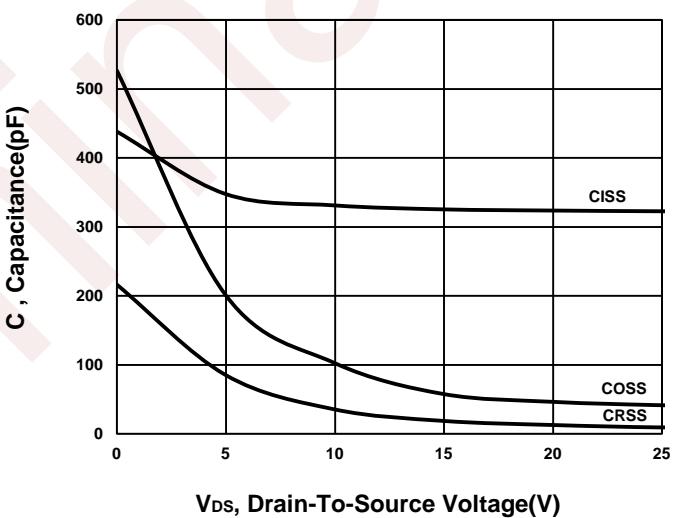
**Transfer Characteristics**



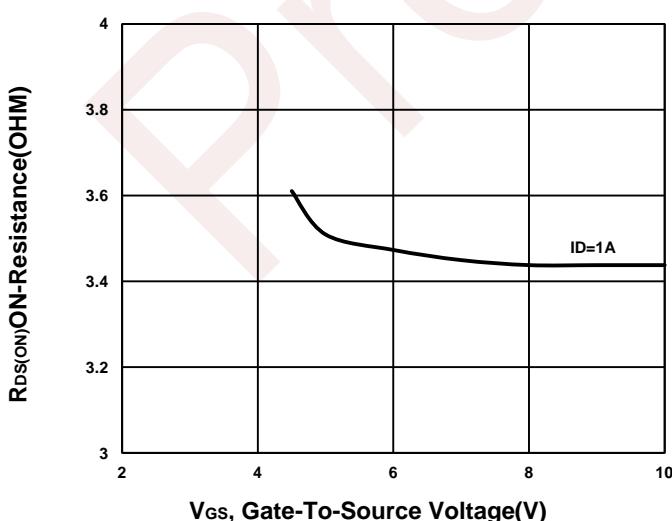
**Gate charge Characteristics**



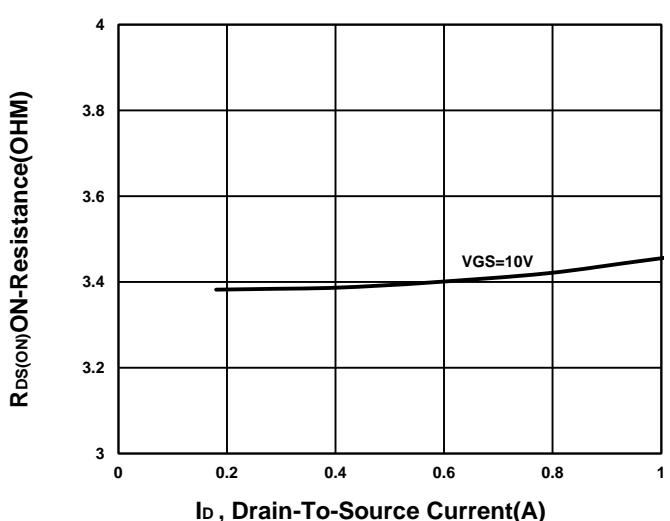
**Capacitance Characteristic**

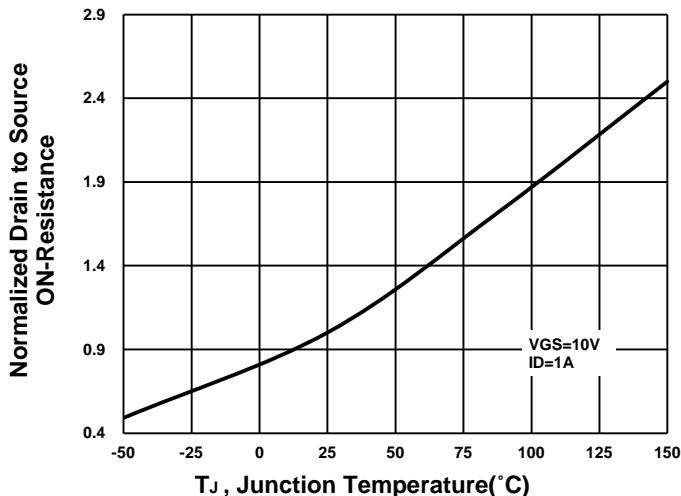
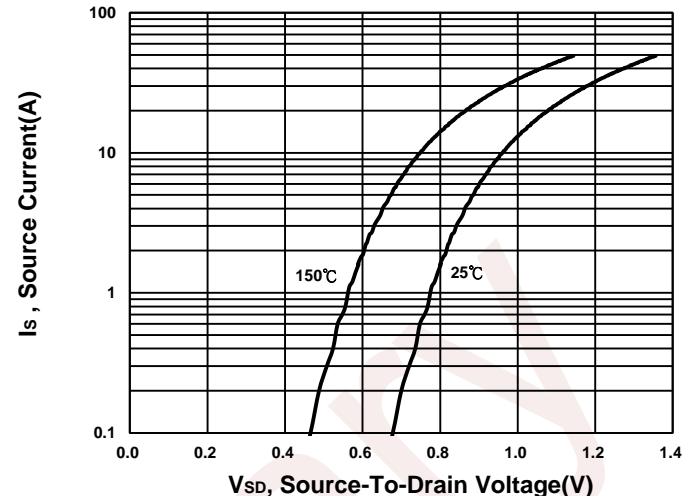
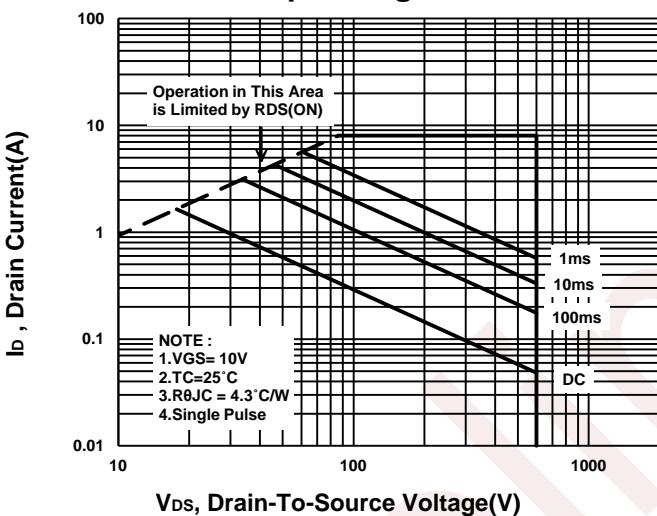
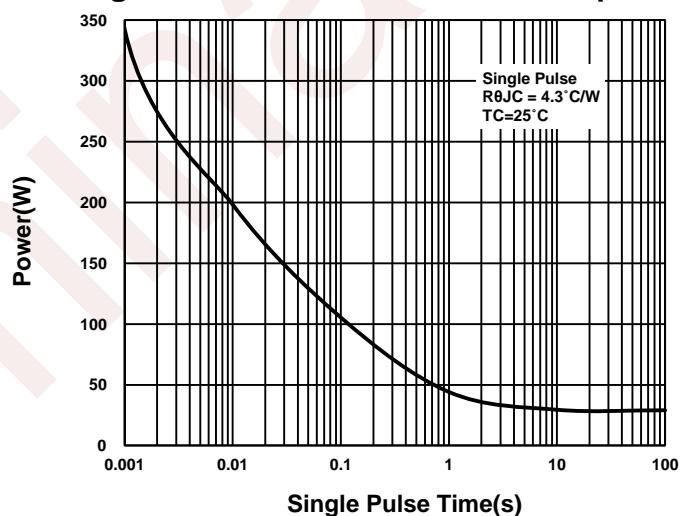


**On-Resistance VS Gate-To-Source**



**On-Resistance VS Drain Current**



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**On-Resistance VS Temperature****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**